DGG OR DL PACKAGE (TOP VIEW)

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- State-of-the-Art Advanced BiCMOS Technology (ABT) Design for 3.3-V **Operation and Low-Static Power** Dissipation
- **Member of the Texas Instruments** Widebus™ Family
- **Supports Mixed-Mode Signal Operation** (5-V Input and Output Voltages With 3.3-V V_{CC})
- **Supports Unregulated Battery Operation** Down to 2.7 V
- Typical V_{OLP} (Output Ground Bounce) $< 0.8 \text{ V at V}_{CC} = 3.3 \text{ V}, T_A = 25^{\circ}\text{C}$
- Bus Hold on Data Inputs Eliminates the **Need for External Pullup/Pulldown** Resistors
- **Supports Live Insertion**
- Distributed V_{CC} and GND Pin Configuration **Minimizes High-Speed Switching Noise**
- Flow-Through Architecture Optimizes **PCB Layout**
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages Using 25-mil **Center-to-Center Spacings**

description

The SN74LVT16835 is an 18-bit universal bus driver designed for low-voltage (3.3-V) V_{CC} operation, but with the capability to provide a TTL interface to a 5-V system environment.

Data flow from A to Y is controlled by the output-enable (OE) input. This device operates in

the transparent mode when the latch-enable (LE)

input is high. The A data is latched if the clock (CLK) input is held at a high or low logic level. If LE is low, the A-bus data is stored in the latch/flip-flop on the low-to-high transition of the clock. When $\overline{\sf OE}$ is high, the outputs are in the high-impedance state.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

To ensure the high-impedance state during power up or power down, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN74LVT16835 is available in Tl's shrink small-outline (DL) and thin shrink small-outline (DGG) packages, which provide twice the input/output (I/O) pins and functionality of standard small-outline packages in the same printed circuit board area.

The SN74LVT16835 is characterized for operation from -40°C to 85°C.



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ISTRUMENTS

56 GND NC [NC 2 55 NC Y1 | 3 54 A1 GND 4 53 GND Y2**∏**5 52 A2 51 A3 Y3∏6 V_{CC} **1**7 50 [] V_{CC} 49 🛮 A4 Y4 | 8 Y5∏9 48 🛮 A5 Y6 10 47 🛮 A6 GND [11 46∏ GND Y7 | 12 45 🛮 A7 Y8 🛮 13 44 🛮 A8 Y9 ∏ 14 43**∏** A9 Y10 🛮 15 42**∏** A10 Y11 **∏** 16 41 **∏** A11 Y12 17 40**∏** A12 GND 18 39 **∏** GND Y13 19 38 A13 Y14 ∏ 20 37 **1** A14 Y15 | 21 36∏ A15 35 [] V_{CC} V_{CC} 1 22 Y16 23 34 A16 Y17 **1**24 33**∏** A17 GND ∏ 25 32 **∏** GND Y18**∏**26 31 **1** A18 30 T CLK OE [] 27

NC - No internal connection

29 **∏** GND

LE [] 28

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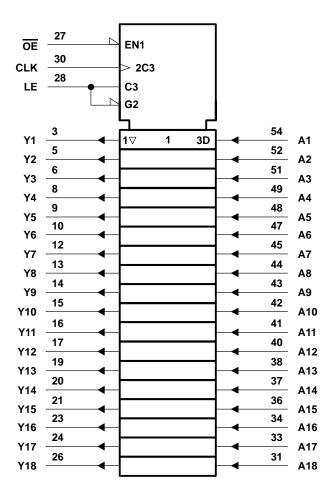
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FUNCTION TABLE

	OUTPUT			
ŌĒ	LE	CLK	Α	Υ
Н	Х	Х	Χ	Z
L	Н	Χ	L	L
L	Н	Χ	Н	Н
L	L	\uparrow	L	L
L	L	\uparrow	Н	Н
L	L	Н	Χ	Y ₀ †
L	L	L	Χ	Y ₀ ‡

[†] Output level before the indicated steady-state input conditions were established, provided that CLK was high before LE went low

logic symbol§



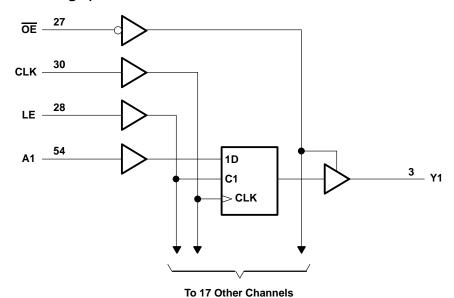
[§] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



[‡] Output level before the indicated steady-state input conditions were established

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logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage range, V _{CC}	–0.5 V to 4.6 V
Input voltage range, V _I (see Note 1)	–0.5 V to 7 V
Voltage range applied to any output in the high state or power-off state, VO (see Note 1)	0.5 V to 7 V
Current into any output in the low state, IO	128 mA
Current into any output in the high state, IO (see Note 2)	64 mA
Input clamp current, I _{IK} (V _I < 0)	
Output clamp current, I _{OK} (V _O < 0)	
Maximum power dissipation at T _A = 55°C (in still air) (see Note 3): DGG package	1 W
DL package	1.4 W
Operating free-air temperature range, T _A	–40°C to 85°C
Storage temperature range, T _{stg}	–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
 - 2. This current flows only when the output is in the high state and $V_O > V_{CC}$.
 - 3. The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils. For more information, refer to the *Package Thermal Considerations* application note in the *ABT Advanced BiCMOS Technology Data Book*.



SN74LVT16835 3.3-V ABT 18-BIT UNIVERSAL BUS DRIVER WITH 3-STATE OUTPUTS

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recommended operating conditions (see Note 4)

			MIN	MAX	UNIT
Vcc	Supply voltage		2.7	3.6	V
VIH	High-level input voltage		2		V
VIL	Low-level input voltage			0.8	V
VI	Input voltage			5.5	V
loh	High-level output current			-32	mA
loL	Low-level output current			64	mA
Δt/Δν	Input transition rise or fall rate	Outputs enabled		10	ns/V
TA	Operating free-air temperature		-40	85	°C

NOTE 4: Unused control inputs must be held high or low to prevent them from floating.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PAI	RAMETER	1	TEST CONDITIONS		MIN	TYP [†]	MAX	UNIT		
VIK		$V_{CC} = 2.7 \text{ V},$ $I_{I} = -18 \text{ mA}$				-1.2	V			
V _{OH}		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}, \qquad I_{OH} = -100 \mu\text{A}$		V _{CC} -0.	.2					
		$V_{CC} = 2.7 \text{ V}, \qquad I_{OH} = -8 \text{ mA}$		2.4			V			
		V _{CC} = 3 V	I _{OH} = -32 mA		2					
		V _{CC} = 2.7 V	I _{OL} = 100 μA				0.2			
		VCC = 2.7 V	I _{OL} = 24 mA				0.5			
VOL			I _{OL} = 16 mA				0.4	٧		
		V _{CC} = 3 V	I _{OL} = 32 mA				0.5			
			I _{OL} = 64 mA				0.55			
		$V_{CC} = 0 \text{ or } 3.6 \text{ V},$	V _I = 5.5 V				10			
	Control inputs	$V_{CC} = 3.6 \text{ V},$	$V_I = V_{CC}$ or GND				±1			
l _l	A inputs	V _{CC} = 3.6 V	$V_I = V_{CC}$				1	μΑ		
			V _I = 5.5 V				20			
			V _I = 0				– 5			
l _{off}	•	V _{CC} = 0,	V_{I} or $V_{O} = 0$ to 4.5 V				±100	μΑ		
	A innute	V 2V	V _I = 0.8 V		75			^		
I(hold)	A inputs	V _{CC} = 3 V	V _I = 2 V		-75			μΑ		
lozh		V _{CC} = 3.6 V,	V _O = 3 V				1	μΑ		
lozL		V _{CC} = 3.6 V,	V _O = 0.5 V				-1	μΑ		
	V _{CC} = 3.6 V, V _I = V _{CC} or GND		I _O = 0,	Outputs high			0.12			
ICC				Outputs low			5	mA		
		AL = ACC OLOND		Outputs disabled			0.12			
∆I _{CC} ‡		V _{CC} = 3 V to 3.6 V, Other inputs at V _{CC} or GND	One input at V _{CC} – 0.6 V,				0.2	mA		
C.	Control inputs					3.5		n.E		
Ci	Data pins	$V_{I} = 3 \text{ V or } 0$				4.5		pF		
Co		V _O = 3 V or 0				11		pF		

[†] All typical values are at $V_{CC} = 3.3 \text{ V}$, $T_A = 25^{\circ}\text{C}$.



[‡] This is the increase in supply current for each input that is at the specified TTL voltage level rather than V_{CC} or GND.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1)

				V _{CC} = 3.3 V ± 0.3 V		V _{CC} = 2.7 V	
			MIN	MAX	MIN	MAX	
fclock	Clock frequency		0	150	0	125	MHz
	Pulse duration LE high CLK high of	LE high	3.3		3.3		ns
t _W		CLK high or low	3.3		3.3		
	Setup time	Data before CLK↑	1.6		2.1		
t _{su}		Data before LE↓, CLK high	2.6		1.9		ns
		Data before LE↓, CLK low	2		1.3		
th	Hald Co.	Data after CLK↑	2		2.1		
	Hold time Data after LE↓			·	1.2		ns

switching characteristics over recommended operating free-air temperature range, C_L = 50 pF (unless otherwise noted) (see Figure 1)

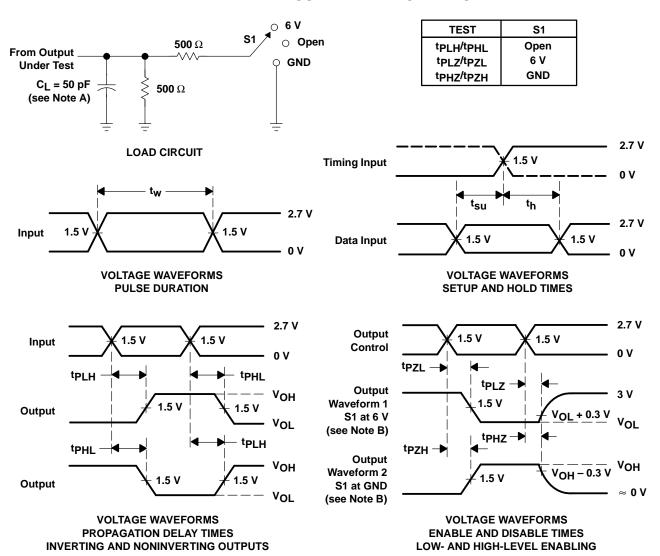
PARAMETER	FROM (INPUT)	TO (OUTPUT)	V_{CC} = 3.3 V \pm 0.3 V			V _{CC} = 2.7 V		UNIT
PARAMETER			MIN	TYP [†]	MAX	MIN	MAX	UNIT
f _{max}			150			150		MHz
tPLH	А	Y	1.7	3	5.4		6.8	ns
^t PHL			1.6	3.2	5.9		7.7	
t _{PLH}	LE	Y	2.3	4	7		8.5	ns
^t PHL		ı	2.7	4.3	7.9		9.7	115
t _{PLH}	CLK	Y	2.5	4.1	7.9		9.2	ns
^t PHL		ı	3.5	5.4	8.9		10.4	115
^t PZH	ŌĒ	Y	1.2	3	5		5.9	ns
tPZL		ı	1.5	3	5.8		6.9	115
^t PHZ	ŌĒ	Y	2.7	4.6	7.4		8.3	ns
^t PLZ		1	2.8	4.7	6.7		7.2	110

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.



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PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_I includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_O = 50 \Omega$, $t_f \leq$ 2.5 ns, $t_f \leq$ 2.5 ns.
- D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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